

Symbol	Typ	Titel
G	Sektion	PHYSICS
G01	Untersektion	INSTRUMENTS
G01	Klasse	MEASURING; TESTING
G01Q	Unterklasse	SCANNING-PROBE TECHNIQUES OR APPARATUS; APPLICATIONS OF SCANNING-PROBE TECHNIQUES, e.g. SCANNING-PROBE MICROSCOPY [SPM] [2010.01]
G01Q 10/00	Hauptgruppe	Scanning or positioning arrangements, i.e. arrangements for actively controlling the movement or position of the probe [2010.01]
G01Q 10/02	1-Punkt Untergruppe	. Coarse scanning or positioning [2010.01]
G01Q 10/04	1-Punkt Untergruppe	. Fine scanning or positioning [2010.01]
G01Q 10/06	2-Punkt Untergruppe	. . Circuits or algorithms therefor [2010.01]
G01Q 20/00	Hauptgruppe	Monitoring the movement or position of the probe [2010.01]
G01Q 20/02	1-Punkt Untergruppe	. by optical means [2010.01]
G01Q 20/04	1-Punkt Untergruppe	. Self-detecting probes, i.e. wherein the probe itself generates a signal representative of its position, e.g. piezo-electric gauge [2010.01]
G01Q 30/00	Hauptgruppe	Auxiliary means serving to assist or improve the scanning probe techniques or apparatus, e.g. display or data processing devices [2010.01]
G01Q 30/02	1-Punkt Untergruppe	. Non-SPM analysing devices, e.g. SEM [Scanning Electron Microscope], spectrometer or optical microscope [2010.01]
G01Q 30/04	1-Punkt Untergruppe	. Display or data processing devices [2010.01]
G01Q 30/06	2-Punkt Untergruppe	. . for error compensation [2010.01]
G01Q 30/08	1-Punkt Untergruppe	. Means for establishing or regulating a desired environmental condition within a sample chamber [2010.01]
G01Q 30/10	2-Punkt Untergruppe	. . Thermal environment [2010.01]
G01Q 30/12	2-Punkt Untergruppe	. . Fluid environment [2010.01]
G01Q 30/14	3-Punkt Untergruppe	. . . Liquid environment [2010.01]
G01Q 30/16	2-Punkt Untergruppe	. . Vacuum environment [2010.01]
G01Q 30/18	1-Punkt Untergruppe	. Means for protecting or isolating the interior of a sample chamber from external environmental conditions or influences, e.g. vibrations or electromagnetic fields [2010.01]
G01Q 30/20	1-Punkt Untergruppe	. Sample handling devices or methods [2010.01]
G01Q 40/00	Hauptgruppe	Calibration, e.g. of probes [2010.01]
G01Q 40/02	1-Punkt Untergruppe	. Calibration standards or methods of fabrication thereof [2010.01]
G01Q 60/00	Hauptgruppe	Particular types of SPM [Scanning-Probe Microscopy] or apparatus therefor; Essential components thereof [2010.01]
G01Q 60/02	1-Punkt Untergruppe	. Multiple-type SPM, i.e. involving two or more SPM techniques [2010.01]
G01Q 60/04	2-Punkt Untergruppe	. . STM [Scanning Tunnelling Microscopy] combined with AFM [Atomic Force Microscopy] [2010.01]
G01Q 60/06	2-Punkt Untergruppe	. . SNOM [Scanning Near-field Optical Microscopy] combined with AFM [Atomic Force Microscopy] [2010.01]
G01Q 60/08	2-Punkt Untergruppe	. . MFM [Magnetic Force Microscopy] combined with AFM [Atomic Force Microscopy] [2010.01]
G01Q 60/10	1-Punkt Untergruppe	. STM [Scanning Tunnelling Microscopy] or apparatus therefor, e.g. STM probes [2010.01]

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G01Q 60/12	2-Punkt Untergruppe	. . STS [Scanning Tunnelling Spectroscopy] [2010.01]
G01Q 60/14	2-Punkt Untergruppe	. . STP [Scanning Tunnelling Potentiometry] [2010.01]
G01Q 60/16	2-Punkt Untergruppe	. . Probes, their manufacture or their related instrumentation, e.g. holders [2010.01]
G01Q 60/18	1-Punkt Untergruppe	. SNOM [Scanning Near-Field Optical Microscopy] or apparatus therefor, e.g. SNOM probes [2010.01]
G01Q 60/20	2-Punkt Untergruppe	. . Fluorescence [2010.01]
G01Q 60/22	2-Punkt Untergruppe	. . Probes, their manufacture or their related instrumentation, e.g. holders [2010.01]
G01Q 60/24	1-Punkt Untergruppe	. AFM [Atomic Force Microscopy] or apparatus therefor, e.g. AFM probes [2010.01]
G01Q 60/26	2-Punkt Untergruppe	. . Friction force microscopy [2010.01]
G01Q 60/28	2-Punkt Untergruppe	. . Adhesion force microscopy [2010.01]
G01Q 60/30	2-Punkt Untergruppe	. . Scanning potential microscopy [2010.01]
G01Q 60/32	2-Punkt Untergruppe	. . AC mode [2010.01]
G01Q 60/34	3-Punkt Untergruppe	. . . Tapping mode [2010.01]
G01Q 60/36	2-Punkt Untergruppe	. . DC mode [2010.01]
G01Q 60/38	2-Punkt Untergruppe	. . Probes, their manufacture or their related instrumentation, e.g. holders [2010.01]
G01Q 60/40	3-Punkt Untergruppe	. . . Conductive probes [2010.01]
G01Q 60/42	3-Punkt Untergruppe	. . . Functionalisation [2010.01]
G01Q 60/44	1-Punkt Untergruppe	. SICM [Scanning Ion-Conductance Microscopy] or apparatus therefor, e.g. SICM probes [2010.01]
G01Q 60/46	1-Punkt Untergruppe	. SCM [Scanning Capacitance Microscopy] or apparatus therefor, e.g. SCM probes [2010.01]
G01Q 60/48	2-Punkt Untergruppe	. . Probes, their manufacture or their related instrumentation, e.g. holders [2010.01]
G01Q 60/50	1-Punkt Untergruppe	. MFM [Magnetic Force Microscopy] or apparatus therefor, e.g. MFM probes [2010.01]
G01Q 60/52	2-Punkt Untergruppe	. . Resonance [2010.01]
G01Q 60/54	2-Punkt Untergruppe	. . Probes, their manufacture or their related instrumentation, e.g. holders [2010.01]
G01Q 60/56	3-Punkt Untergruppe	. . . Probes with magnetic coating [2010.01]
G01Q 60/58	1-Punkt Untergruppe	. SThM [Scanning Thermal Microscopy] or apparatus therefor, e.g. SThM probes [2010.01]
G01Q 60/60	1-Punkt Untergruppe	. SECM [Scanning Electro-Chemical Microscopy] or apparatus therefor, e.g. SECM probes [2010.01]
G01Q 70/00	Hauptgruppe	General aspects of SPM probes, their manufacture or their related instrumentation, insofar as they are not specially adapted to a single SPM technique covered by group G01Q 60/00 [2010.01]
G01Q 70/02	1-Punkt Untergruppe	. Probe holders [2010.01]
G01Q 70/04	2-Punkt Untergruppe	. . with compensation for temperature or vibration induced errors [2010.01]
G01Q 70/06	1-Punkt Untergruppe	. Probe tip arrays [2010.01]
G01Q 70/08	1-Punkt Untergruppe	. Probe characteristics [2010.01]
G01Q 70/10	2-Punkt Untergruppe	. . Shape or taper [2010.01]
G01Q 70/12	3-Punkt Untergruppe	. . . Nanotube tips [2010.01]

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G01Q 70/14	2-Punkt Untergruppe	. . Particular materials [2010.01]
G01Q 70/16	1-Punkt Untergruppe	. Probe manufacture [2010.01]
G01Q 70/18	2-Punkt Untergruppe	. . Functionalisation [2010.01]
G01Q 80/00	Hauptgruppe	Applications, other than SPM, of scanning-probe techniques (manufacture or treatment of microstructures B81C; manufacture or treatment of nanostructures B82B 3/00; recording or reproducing information using near-field interaction G11B 9/12, G11B 11/24 or G11B 13/08) [2010.01]
G01Q 90/00	Hauptgruppe	Scanning-probe techniques or apparatus not otherwise provided for [2010.01]